

Notice of Allowability	Application No.	Applicant(s)	
	10/644,717	NAGASAWA, JUN	
	Examiner	Art Unit	
	John H Le	2863	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☐ This communication is responsive to _____.
2. ☒ The allowed claim(s) is/are 1-4.
3. ☒ The drawings filed on 20 August 2003 are accepted by the Examiner.
4. ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) ☐ All b) ☐ Some* c) ☒ None of the:
 1. ☒ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

* Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.
THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

5. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
6. ☐ CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
 - (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
 - 1) ☐ hereto or 2) ☐ to Paper No./Mail Date _____.
 - (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.

Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
7. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

- | | |
|---|--|
| 1. <input checked="" type="checkbox"/> Notice of References Cited (PTO-892) | 5. <input type="checkbox"/> Notice of Informal Patent Application (PTO-152) |
| 2. <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | 6. <input type="checkbox"/> Interview Summary (PTO-413),
Paper No./Mail Date _____. |
| 3. <input type="checkbox"/> Information Disclosure Statements (PTO-1449 or PTO/SB/08),
Paper No./Mail Date _____ | 7. <input checked="" type="checkbox"/> Examiner's Amendment/Comment |
| 4. <input type="checkbox"/> Examiner's Comment Regarding Requirement for Deposit
of Biological Material | 8. <input checked="" type="checkbox"/> Examiner's Statement of Reasons for Allowance |
| | 9. <input type="checkbox"/> Other _____. |

Examiner's Amendment

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Attorney Franco S. De Ligouri on 01/13/2005.

The applicant has been amended as follows:

In the specification:

Paragraph beginning at line 3, after the title, of page 1 has been amended as follows:

The present invention relates to an analysis apparatus such as a thermal analyzer, and ~~etc.~~ and in particular relates to an analysis apparatus for consecutively measuring a plurality of samples.

Paragraph beginning at line 9 of page 4 has been amended as follows:

An ~~advantage~~ object of the ~~present invention, it~~ invention is to provide an analysis apparatus capable of designating arbitrary calibration conditions for each measurement when a plurality of types of measurement are carried out using an autosampler, ~~etc.~~

Paragraph beginning at line 14 of page 4 has been amended as

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follows:

An analysis apparatus of the present invention comprises a measurement head for measuring sample characteristics; storage means for storing calibration conditions made by performing device calibration in advance; a measurement sequence data capable of setting calibration conditions used in each measurement step; designation means for designating calibration conditions for each measurement step of a the measurement sequence data; and measurement control means for controlling a series of measurements in accordance with a the measurement sequence, ~~for sequence data and for~~ carrying out measurement after first setting calibration conditions designated for each measurement step at the measurement head when executing each measurement step.

Paragraph beginning at line 15 of page 6 has been amended as follows:

The measurement station 20 comprises a measurement head controller a measurement sequence 22 containing measurement sequence data, a calibration conditions file 23, a temperature program file 24, and input means 25. The measurement sequence 22 is an arrangement for a measurement procedure for carrying out a plurality of measurements and is comprised of a plurality of measurement conditions and calibration conditions having an execution order.

In the following, one measurement procedure within a measurement sequence is referred to as a measurement step.

In the Claims:

Amend claims 1-4 as follows:

1. (currently amended) An analysis apparatus comprising:
a measurement head for measuring ~~sample~~ characteristics of
a sample;
a calibration conditions file comprising at least one
calibration condition ~~made~~ obtained by carrying out device
calibration for the measurement head in advance;
designation means for designating one of the calibration
conditions within the calibration conditions file;
a measurement sequence ~~comprising~~ data comprised of data representing a
sequence ~~for a plurality~~ of measurement steps comprising measurement
conditions for carrying out measurements by the measurement head
and the calibration conditions designated by the designation
means; and
measurement means for referring to each measurement step
of the measurement sequence and carrying out measurement after
inputting the measurement conditions and the calibration
conditions for each measurement step to the measurement head.
2. (currently amended) ~~The~~ An analysis apparatus according

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to ~~claim 1, further~~ claim 1; further comprising means for saving calibration conditions ~~made~~ obtained by carrying out device calibration on the measurement head in advance as a file in the calibration conditions file and designating the calibration conditions used in each measurement step in the measurement sequence using a calibration conditions file name.

3. (currently amended) ~~The~~ An analysis apparatus according to ~~claim 1, characterized by a~~ claim 1 ; wherein the analysis apparatus is a thermal analysis apparatus; and wherein ~~equipped with a furnace for heating the sample at the measurement head~~ has a furnace for heating the sample and control means for ~~and~~ measuring physical characteristics of the sample while varying the changing temperature of the furnace.

4.(currently amended) ~~The~~ An analysis apparatus according to ~~claim 2, characterized by a~~ claim 2; wherein the analysis apparatus is a thermal analysis apparatus; and wherein ~~equipped with a furnace for heating a sample at the measurement head~~ has a furnace for heating the sample and control means for ~~and~~ measuring physical characteristics of the sample while varying the changing temperature of the furnace.

In the Abstract:

Replace the original abstract with the following new abstract:

An analysis apparatus has a measurement head for measuring characteristics of a sample, a calibration conditions file comprising at least one calibration condition obtained by carrying out device calibration for the measurement head in advance, and a measurement head controller for designating one of the calibration conditions within the calibration conditions file. Measurement sequence data comprised of a sequence of measurement steps has measurement conditions for carrying out measurements by the measurement head and the calibration conditions designated by the measurement head controller. A measurement device refers to each measurement step of the measurement sequence data and carries out measurement after inputting the measurement conditions and the calibration conditions for each measurement step to the measurement head.

Reasons for Allowance

2. Claims 1-4 are allowed.
3. The following is a statement of reasons for the indication of allowable subject matter:

In combination with other limitations of the claims, the cited prior arts fails to teach designation means for designating one of the calibration conditions within the calibration conditions file; measurement sequence data comprised of data representing a sequence of measurement steps comprising measurement conditions for carrying out measurements by the measurement head and the calibration conditions designated by the designation means; and measurement means for referring to each measurement step of the sequence and carrying out measurement after inputting the measurement

conditions and the calibration conditions for each measurement step to the measurement head, as recited in amended claim(s) 1.

U.S. Patent No. 6,782,332 discloses an ultrasound transducer temperature compensation methods, apparatus and programs. A software program may be used to compute the temperature dependent calibration parameters. '332 fails to specify a designation means for designating one of the calibration conditions within the calibration conditions file; measurement sequence data comprised of data representing a sequence of measurement steps comprising measurement conditions for carrying out measurements by the measurement head and the calibration conditions designated by the designation means; and measurement means for referring to each measurement step of the sequence and carrying out measurement after inputting the measurement conditions and the calibration conditions for each measurement step to the measurement head, as now recited in claim 1 of the present invention.

U.S. Patent No. 6,622,104 discloses a heat treatment apparatus has a controller provided with a temperature estimator for estimating a temperature of a wafer by detection signals of temperature sensors and a temperature calibrator for correcting the estimated temperature of the wafer. '104 fails to specify designation means for designating one of the calibration conditions within the calibration conditions file; measurement sequence data comprised of data representing a sequence of measurement steps comprising measurement conditions for carrying out measurements by the measurement head and the calibration conditions designated by the designation means; and measurement means for referring to each measurement step of the

sequence and carrying out measurement after inputting the measurement conditions and the calibration conditions for each measurement step to the measurement head, as now recited in claim 1 of the present invention.

U.S. Patent No. 5,025,653 discloses a gas detection system for detecting the content of gases, comprising a plurality of measuring heads, each said head being positioned at a measuring point, each said measuring head being equipped for connection with a least one sensor, said sensors being one of the same and different types, sensors of the same type having one of the same and different measuring ranges; a central electronic evaluation system being connected to said plurality of measuring heads and said measuring heads being adapted for bidirectional digital communication and, simultaneously, for supplying electrical operating current to said measuring heads. '653 fails to specify designation means for designating one of the calibration conditions within the calibration conditions file; measurement sequence data comprised of data representing a sequence of measurement steps comprising measurement conditions for carrying out measurements by the measurement head and the calibration conditions designated by the designation means; and measurement means for referring to each measurement step of the sequence and carrying out measurement after inputting the measurement conditions and the calibration conditions for each measurement step to the measurement head, as now recited in claim 1 of the present invention.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably

accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Contact Information

4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to John H Le whose telephone number is 571-272-2275. The examiner can normally be reached on 8:00 - 4:30.


If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John E Barlow can be reached on 571-272-2269. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

John H. Le

Patent Examiner-Group 2863

January 14, 2005


John Barlow
Supervisory Patent Examiner
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